

What is claimed is:

1. A solid state image device in which solid state image elements of N lines in vertical direction and M pixels in horizontal direction are arranged in a matrix shape, said solid state image device comprising:

5 display means for displaying a position of a defective pixel occurred in said solid state element on a screen,

position selection means for being manually operated so as to select a position of a defective pixel on a screen of said display means, and

10 memory means for recording positional information of a defective pixel selected by said position selection means.

2. A solid state image device according to claim 1, wherein said position selection means has,

15 horizontal cursor operated in vertical direction on a screen of said display means,

vertical cursor operated in horizontal direction on said screen, and

20 writing determination button operated so as to be pressed at an intersection of said horizontal cursor and vertical cursor.

3. A solid state image device according to claim 1, wherein as for said solid state image element, a case where an image is divided into three of red, green and blue and acquired, in said case,

25 a horizontal cursor operated in vertical direction on a screen of said display means is displayed in white, and

a vertical cursor operated in horizontal direction on said screen is

displayed in red, green or blue color.

4. A solid state image device according to claim 1, wherein as for vertical cursor operated in horizontal direction on a screen of said display means,

a position of a defective pixel already recorded in said memory means is lighted and displayed in red, green or blue color,

a position of a defective pixel about to be recorded in said memory means from now is flickered and displayed in red, green and blue color.

5. A solid state image device according to claim 1, wherein a case where an operation determining a writing by superimposing an intersection of said horizontal cursor and said vertical cursor on a position of said defective pixel is made as a manual writing mode,

an operation determining a writing by detecting a position of said defective pixel and automatically scanning an acquisition image acquired by said solid state image element is made as an automated writing mode, and

mode selection means for selecting either of said automated writing mode or said manual writing mode is provided.

6. A solid state image device according to claim 1, wherein a writing area from first line to the N line is assigned so as to previously write positional information of defective pixels of m pieces portion per one line, and it is performed so that positional information of a defective pixel occurred on the relevant line of said solid state image element is recorded in a writing area corresponding to the relevant line of said memory

means.

7. A solid state image device according to claim 1, wherein defect detection means for detecting positional information of a defective pixel occurred on the relevant line of said solid state image element, and

information writing and reading means for recording positional information of a defective pixel detected by said defect detection means in a writing area of said memory means corresponding to the relevant line and reading positional information from said writing area are provided.

8. A solid state image device according to claim 1, wherein information rewriting means for deleting positional information of a defective pixel recorded in said memory means and rewriting the relevant positional information is provided.

9. A solid state image device according to claim 1, wherein in said defect detection means,

line scanning in turn a solid state image element of N lines and M pixels and measuring luminance by respective solid state image element in a state where an incident light to said solid state image element is intercepted,

comparing respective luminance by said solid state image element and reference luminance previously set, and

detecting positional information of a defective pixel occurred on the relevant line corresponding to said comparative results.

10. A solid state image device according to claim 1, wherein as for

image acquisition information of a solid state image element of a defective pixel recorded in said memory means, at least defect correction means for interpolating image acquisition information of a solid state image element of said defective pixel is provided based on image acquisition information
5 by solid state image elements in front and in the rear of said defective pixel.

11. A defective pixel recording method in a solid state image device in which solid state image elements of N lines in vertical direction
10 and M pixels in horizontal direction are arranged in a matrix shape, wherein

displaying a position of a defective pixel occurred in said solid state image element on a screen,

manually operating and selecting a position of a defective pixel
15 displayed on said screen, and

recording positional information of said selected defective pixel in memory means.

12. A defective pixel recording method of a solid state image device
20 according to claim 11, wherein when a position of a defective pixel displayed on said screen is selected,

displaying horizontal cursor and vertical cursor on said screen simultaneously,

manually operating not only said horizontal cursor in vertical
25 direction and manually operating but also said vertical cursor in horizontal direction, and

determining a writing by superimposing an intersection of said

horizontal cursor and vertical cursor on a position of said defective pixel.

13. A defective pixel recording method of a solid state image device according to claim 11, wherein when a defective pixel which is larger than
5 a defective pixel recorded in said memory means, I sdetected

positional information of a defective pixel recorded in said memory means is deleted and rewritten into new positional information .

14. A defective pixel recording method of a solid state image device
10 according to claim 11, wherein when positional information of said defective pixel is recorded in memory means,

preparing a writing area from first line to Nth line in said memory means so as to previously write defective pixels of m pieces portion per one line, and

15 subsequently, recording positional information of a defective pixel occurred on the relevant line of said solid state image element in a writing area of said memory means corresponding to the relevant line.